## Notice of References Cited Application/Control No. 10/719,319 Applicant(s)/Patent Under Reexamination CHEN ET AL. Examiner Patricia L. Hailey 1755 Applicant(s)/Patent Under Reexamination CHEN ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0191020	10-2003	Bharadwaj et al.	502/334
*	В	US-3,988,259	10-1976	Ray, Gardner C.	502/25
*	O	US-2004/0225165	11-2004	Allison et al.	568/910.5
*	۵	US-2003/0208095	11-2003	Budin et al.	585/658
	ш	US-			
	F	US-			;
	G	US-			
	Н	US-			
	1	US-			
	J	US-	_		
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	a					
	R					
	S					
	Т	•				

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	·
	V	
	w	
	X	·

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

U.S. Patent and Trademark Office
PFO-892 (Rev. 01-2001)